

<<微观组织的分析电子显微学表征>>

图书基本信息

书名：<<微观组织的分析电子显微学表征>>

13位ISBN编号：9787040300925

10位ISBN编号：7040300923

出版时间：2012-1

出版时间：高等教育出版社

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内容概要

本收系统地介绍了分析电子显微学（AEM）的基本概念和操作技术，聚集于相变和形变中位错的AEM研究。同时通过大量的例子阐述衍射晶体学的物理概念和数学分析方法，例如相变中位向关系的定量预测等，以便读者加深理解和拓展视野。

<<微观组织的分析电子显微学表征>>

书籍目录

Chapter 1 Analytical Electron Microscope (AEM)

- 1.1 Brief introduction of AEM history
- 1.2 Interaction between electrons and specimen and signals used by AEM

AEM

- 1.3 Electron wavelength and electromagnetic lens
 - 1.3.1 Electron wavelength
 - 1.3.2 Electromagnetic lens
- 1.4 Structure and function of AEM
 - 1.4.1 Illumination system
 - 1.4.2 Specimen holders
 - 1.4.3 Imaging system
 - 1.4.4 Image recording
 - 1.4.5 Power supply system and vacuum system
 - 1.4.6 Computer control
- 1.5 The principle of imaging, magnifying and diffracting
- 1.6 Theoretical resolution limit
- 1.7 Depth of focus and depth of field
- 1.8 Spherical aberration-corrected TEMs References

Chapter 2 Specimen Preparation

- 2.1 Traditional techniques
 - 2.1.1 Replica
 - 2.1.2 Preparation of powders
 - 2.1.3 Film preparation for plan view
 - 2.1.4 Film preparation from a bulk metallic sample
 - 2.1.5 Film preparation from a bulk nonmetallic sample.
- 2.2 Special techniques
 - 2.2.1 Cross-sectional specimen preparation
 - 2.2.2 Cleaving and small angle cleavage technique
 - 2.2.3 Ultramicrotomy
 - 2.2.4 Focused ion beam technique References

Chapter 3 Electron Diffraction

- 3.1 Comparison of electron diffraction with X-ray diffraction
- 3.2 Conditions of diffraction
 - 3.2.1 Geometric condition
 - 3.2.2 Physical condition
 - 3.2.3 Diffraction deviating from exact Bragg Condition
- 3.3 Basic equation used for analysis of electron diffraction pattern
 - 3.3.1 Diffraction in an electron diffractometer
 - 3.3.2 Diffraction in a TEM
- 3.4 Principle and operation of selected area electron diffraction
- 3.5 Rotation of image relative to diffraction pattern
- 3.6 Diffraction patterns of polycrystal and their

<<微观组织的分析电子显微学表征>>

applications

3.6.1 Formation and geometric features of diffraction patterns

for polycrystal

3.6.2 Applications of ring patterns

3.7 Geometric features of diffraction patterns of single
crystals

3.7.1 Geometric features and diffraction intensity of a single
crystal pattern

3.7.2 Indexing methods of single crystal diffraction

patterns

3.8 Main applications of single crystal pattern

3.8.1 Identification of phases

3.8.2 Determination of orientation relationship

3.9 Diffraction spot shift by stacking faults and determination of
stacking fault probability

3.9.1 Diffraction from planar defect

3.9.2 Determination of stacking fault probability in HCP

crystal

3.9.3 Determination of stacking fault probability in FCC

crystal

3.10 Systematic tilting technique and its applications

3.10.1 Systematic tilting technique by double tilt holder.

3.10.2 Determination of electron beam direction

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Chapter 4 Mathematics Analysis in Electron Diffraction and
Crystallography

Chapter 5 Diffraction Contrast

Chapter 6 High Resolution and High Spatial Resolution of Analytical
electron Microscopy

Appendix

Index

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